

Notice of References Cited	Application/Control No. 10/612,566		Applicant(s)/Patent Under Reexamination YOSHIDA ET AL.	
	Examiner Huan H. Tran		Art Unit 2861	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0066448	04-2004	Hoshino et al.	347/220
*	B	US-6,501,495	12-2002	Ichikawa et al.	347/171
*	C	US-4,397,709	08-1983	Schwenzer, Alfred F.	156/351
*	D	US-5,846,358	12-1998	Nagamoto et al.	156/64
*	E	US-4,784,714	11-1988	Shibata, Tomoo	156/354
*	F	US-4,707,211	11-1987	Shibata, Tomoo	156/354
*	G	US-4,468,274	08-1984	Adachi, Takato	156/320
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 02-117846	05-1990	Japan	Komuro	347/171
	O	JP 03-010875	01-1991	Japan	Teranishi et al	400/701
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.